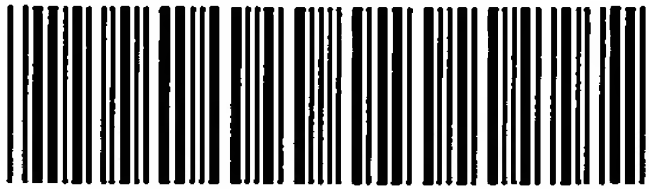


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/654,558	TIAN, KEVIN	
	Examiner	Art Unit	
	Jack W. Lavinder	3677	

SEARCHED			
Class	Subclass	Date	Examiner
63	12,13	12/21/2004	JWL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR